



**THE DATASHEET OF
DMS3019SSD-13**



ASYMMETRIC DUAL N-CHANNEL ENHANCEMENT MODE MOSFET

Features

- DIOFET Utilizes a Unique Patented Process to Monolithically Integrate a MOSFET and a Schottky in a Single Die To Deliver:
 - Low $R_{DS(on)}$ —Minimizes Conduction Loss
 - Low V_{SD} —Reduces Losses Due to Body Diode Construction
 - Low Q_{rr} —Lower Q_{rr} of Integrated Schottky Reduces Body Diode Switching Losses
 - Low Gate Capacitance (Q_g/Q_{gs}) Ratio—Reduces Risk of Shoot-Through or Cross Conduction Currents at High Frequencies
 - Avalanche Rugged— I_{AR} and E_{AR} Rated
- **Totally Lead-Free & Fully RoHS Compliant (Notes 1 & 2)**
- **Halogen and Antimony Free. "Green" Device (Note 3)**
- **Qualified to AEC-Q101 Standards for High Reliability**

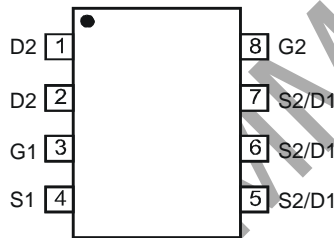
Mechanical Data

- Case: SO-8
- Case Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections: See Diagram Below
- Weight: 0.072 grams (Approximate)

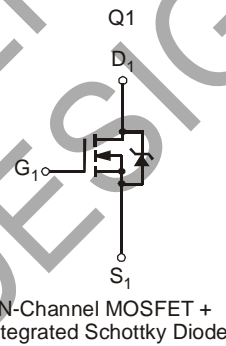
DIOFET



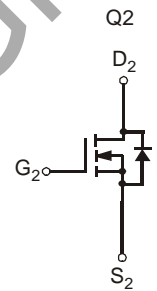
Top View



Top View
Internal Schematic



N-Channel MOSFET +
Integrated Schottky Diode



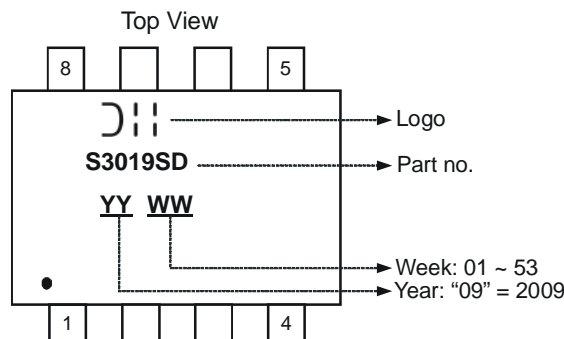
N-Channel MOSFET

Ordering Information (Note 3)

Part Number	Case	Packaging
DMS3019SSD-13	SO-8	2500/Tape & Reel

- Notes:
1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS), 2011/65/EU (RoHS 2) & 2015/863/EU (RoHS 3) compliant.
 2. See <https://www.diodes.com/quality/lead-free/> for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.
 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds
 4. For packaging details, go to our website at <http://www.diodes.com/>.

Marking Information



Maximum Ratings – Q1 @TA = 25°C unless otherwise specified

Characteristic			Symbol	Value	Unit
Drain-Source Voltage			V_{DSS}	30	V
Gate-Source Voltage			V_{GSS}	±12	V
Continuous Drain Current (Note 4) $V_{GS} = 10V$	Steady State	$T_A = 25^\circ C$	I_D	7.0	A
		$T_A = 70^\circ C$		5.6	
Continuous Drain Current (Note 5) $V_{GS} = 10V$	Steady State	$T_A = 25^\circ C$	I_D	9.0	A
		$T_A = 70^\circ C$		7.0	
Continuous Drain Current (Note 5) $V_{GS} = 4.5V$	Steady State	$T_A = 25^\circ C$	I_D	8.0	A
		$T_A = 70^\circ C$		6.5	
Pulsed Drain Current (Note 6)			I_{DM}	40	A
Avalanche Current (Notes 6 & 7)			I_{AR}	13	A
Repetitive Avalanche Energy (Notes 6 & 7) $L = 0.3mH$			E_{AR}	25.4	mJ

Maximum Ratings – Q2 @TA = 25°C unless otherwise specified

Characteristic			Symbol	Value	Unit
Drain-Source Voltage			V_{DSS}	30	V
Gate-Source Voltage			V_{GSS}	±20	V
Continuous Drain Current (Note 4) $V_{GS} = 10V$	Steady State	$T_A = 25^\circ C$	I_D	5.7	A
		$T_A = 70^\circ C$		4.6	
Continuous Drain Current (Note 5) $V_{GS} = 10V$	Steady State	$T_A = 25^\circ C$	I_D	7.0	A
		$T_A = 70^\circ C$		5.6	
Continuous Drain Current (Note 5) $V_{GS} = 4.5V$	Steady State	$T_A = 25^\circ C$	I_D	6.0	A
		$T_A = 70^\circ C$		4.7	
Pulsed Drain Current (Note 6)			I_D	40	A
Avalanche Current (Notes 6 & 7)			I_{AR}	16	A
Repetitive Avalanche Energy (Notes 6 & 7) $L = 0.1mH$			E_{AR}	12.8	mJ

Thermal Characteristics

Characteristic	Symbol	Value	Unit
Power Dissipation (Note 4)	P_D	1.19	W
Thermal Resistance, Junction to Ambient @ $T_A = 25^\circ C$ (Note 4)	$R_{\theta JA}$	107	$^\circ C/W$
Power Dissipation (Note 5)	P_D	1.79	W
Thermal Resistance, Junction to Ambient @ $T_A = 25^\circ C$ (Note 5)	$R_{\theta JA}$	70	$^\circ C/W$
Operating and Storage Temperature Range	T_J, T_{STG}	-55 to +150	$^\circ C$

- Notes:
- Device mounted on FR-4 substrate PCB, with minimum recommended pad layout. The value in any given application depends on the user's specific board design. Device contains two active die running at equal power.
 - Device mounted on 1 inch x 1 inch FR4 PCB with high coverage of single sided 1oz copper, in still air conditions. Device contains two active die running at equal power.
 - Repetitive rating, pulse width limited by junction temperature.
 - I_{AR} and E_{AR} rating are based on low frequency and duty cycles to keep $T_J = 25^\circ C$

Electrical Characteristics – Q1 @ T_A = 25°C unless otherwise stated

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 8)						
Drain-Source Breakdown Voltage	BV _{DSS}	30	—	—	V	V _{GS} = 0V, I _D = 1mA
Zero Gate Voltage Drain Current	I _{DSS}	—	—	0.1	mA	V _{DS} = 30V, V _{GS} = 0V
Gate-Source Leakage	I _{GSS}	—	—	±100	nA	V _{GS} = ±12V, V _{DS} = 0V
ON CHARACTERISTICS (Note 8)						
Gate Threshold Voltage	V _{GS(th)}	1.0	—	2.4	V	V _{DS} = V _{GS} , I _D = 250μA
Static Drain-Source On-Resistance	R _{DS(ON)}	—	10	15	mΩ	V _{GS} = 10V, I _D = 9A
			12	18		V _{GS} = 4.5V, I _D = 7A
Forward Transfer Admittance	Y _{fs}	—	5	—	S	V _{DS} = 5V, I _D = 9A
Diode Forward Voltage	V _{SD}	—	0.4	1	V	V _{GS} = 0V, I _S = 1A
DYNAMIC CHARACTERISTICS (Note 9)						
Input Capacitance	C _{ISS}	—	1932	—	pF	V _{DS} = 15V, V _{GS} = 0V, f = 1.0MHz
Output Capacitance	C _{OSS}	—	154	—		
Reverse Transfer Capacitance	C _{RSS}	—	121	—	Ω	V _{DS} = 0V, V _{GS} = 0V, f = 1MHz
Gate Resistance	R _g	—	2.7	—		
Total Gate Charge (V _{GS} = 4.5V)	Q _g	—	18.1	—	nC	V _{DS} = 15V, V _{GS} = 4.5V, I _D = 9A
Total Gate Charge (V _{GS} = 10V)	Q _g	—	42.0	—		
Gate-Source Charge	Q _{gs}	—	4.5	—		
Gate-Drain Charge	Q _{gd}	—	4.0	—		
Turn-On Delay Time	t _{D(on)}	—	6.16	—	ns	V _{GS} = 10V, V _{DS} = 15V, R _G = 3Ω, R _L = 1.7Ω
Turn-On Rise Time	t _r	—	7.22	—		
Turn-Off Delay Time	t _{D(off)}	—	36.76	—		
Turn-Off Fall Time	t _f	—	5.38	—		

- Notes:
- 8. Short duration pulse test used to minimize self-heating effect.
 - 9. Guaranteed by design. Not subject to production testing.

NOT RECOMMENDED FOR NEW DESIGN

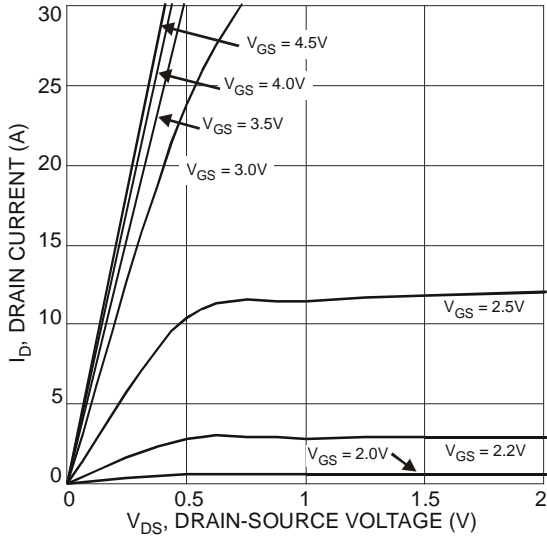


Fig. 1 Typical Output Characteristic

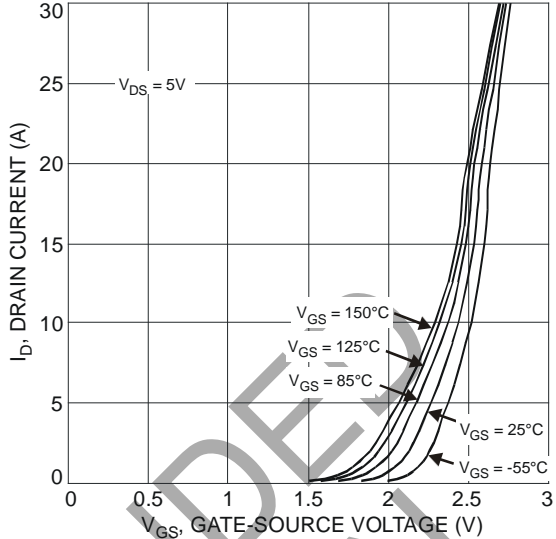


Fig. 2 Typical Transfer Characteristic

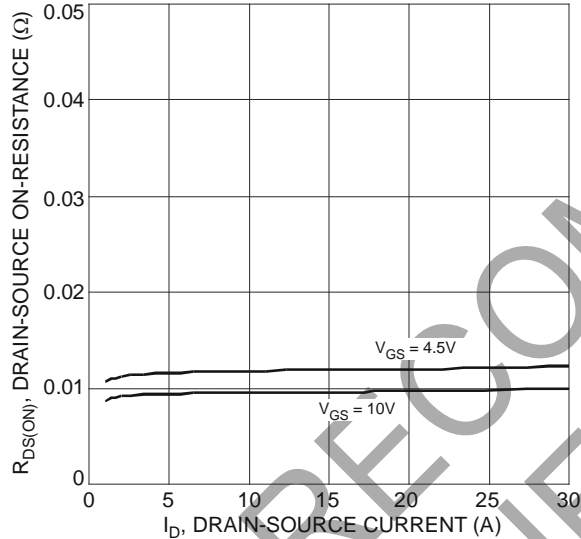


Fig. 3 Typical On-Resistance vs. Drain Current and Gate Voltage

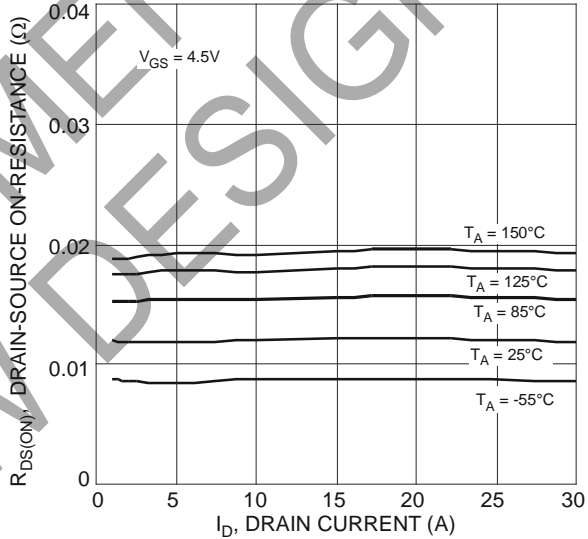


Fig. 4 Typical On-Resistance vs. Drain Current and Temperature

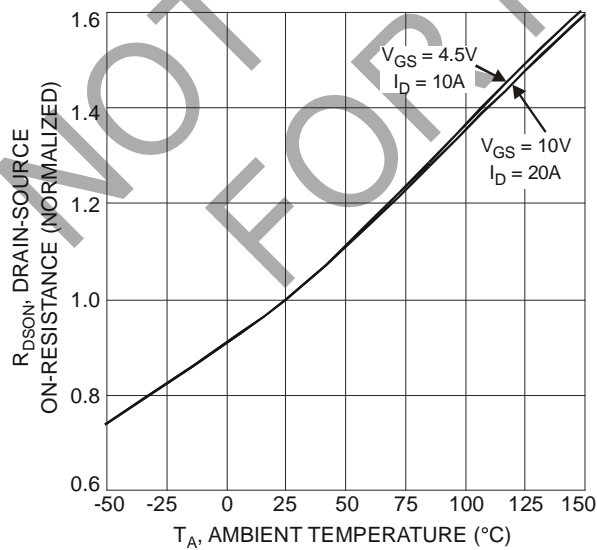


Fig. 5 On-Resistance Variation with Temperature

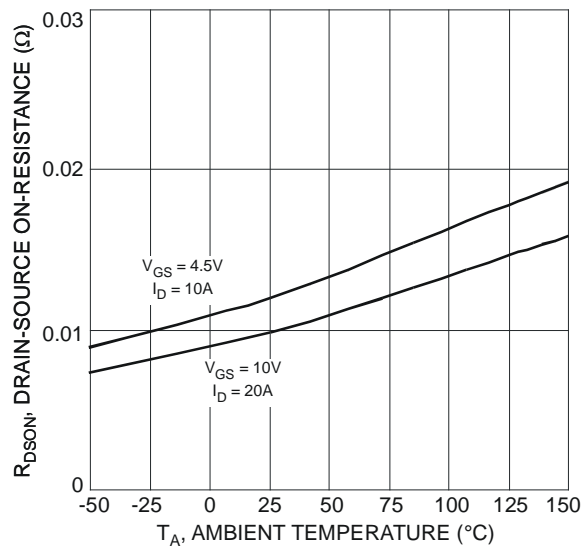


Fig. 6 On-Resistance Variation with Temperature

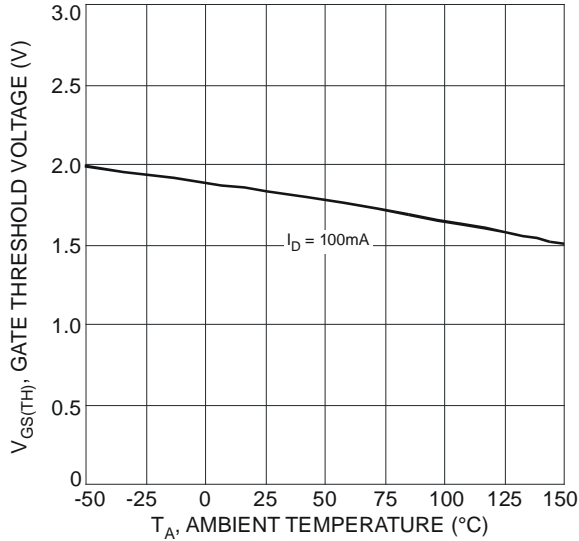


Fig. 7 Gate Threshold Variation vs. Ambient Temperature

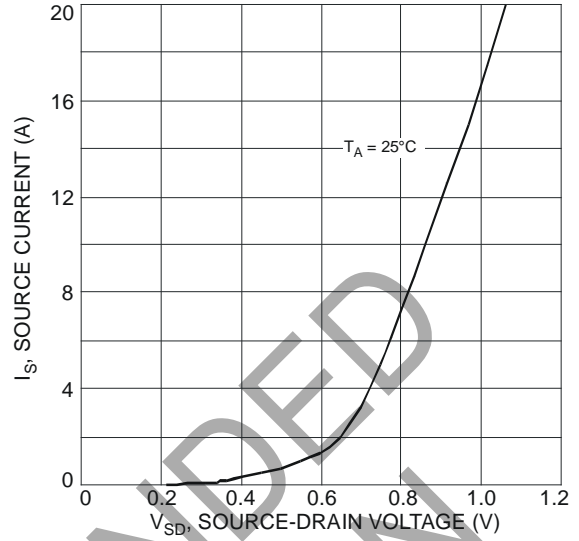


Fig. 8 Diode Forward Voltage vs. Current

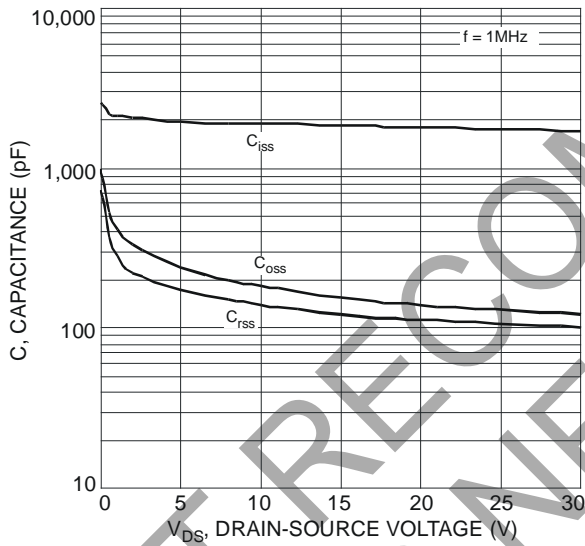


Fig. 9 Typical Total Capacitance

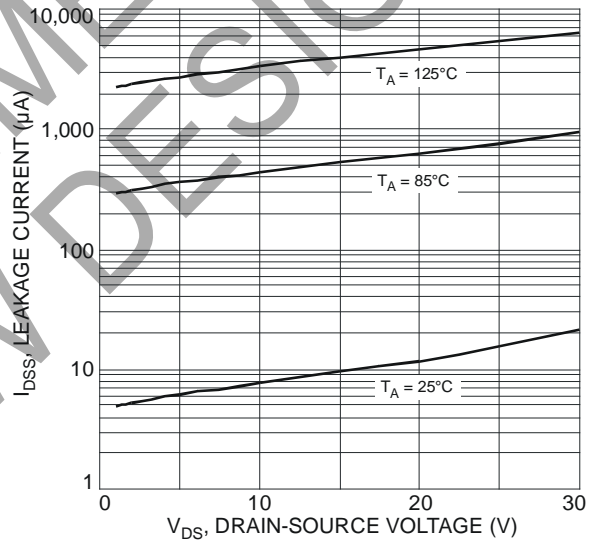


Fig. 10 Typical Leakage Current vs. Drain-Source Voltage

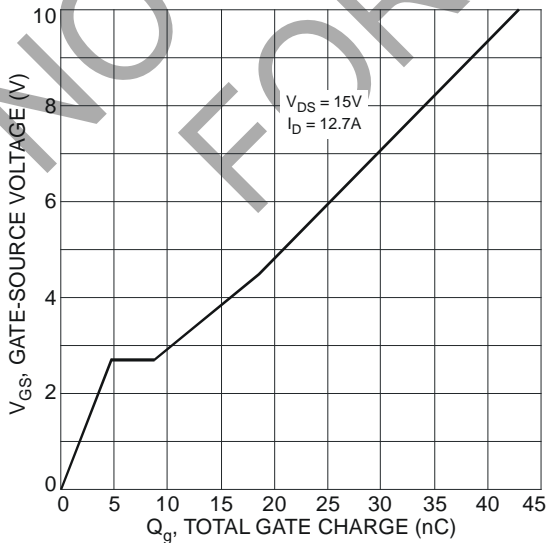
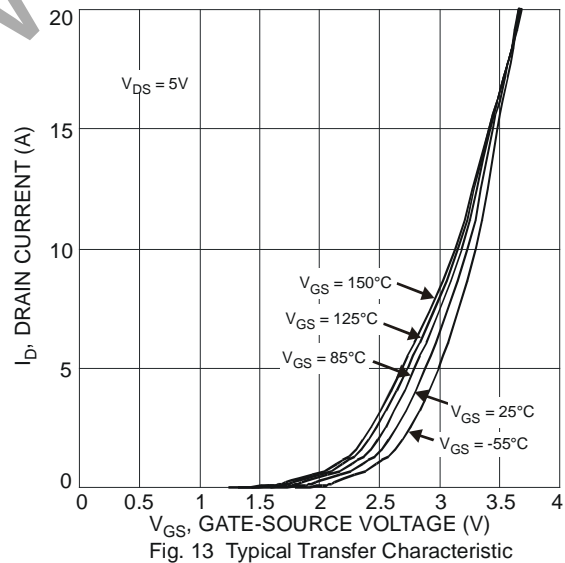
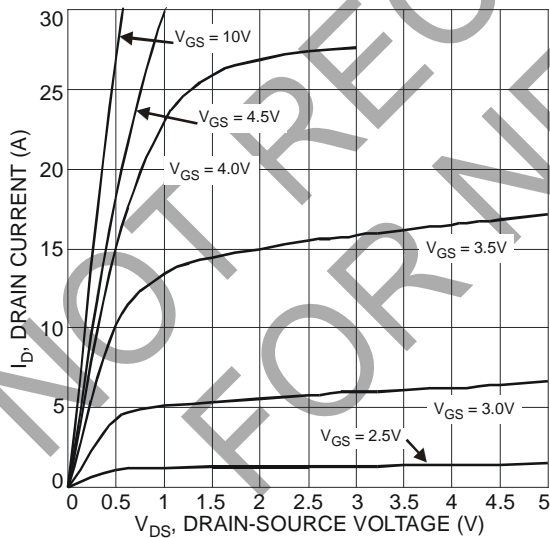


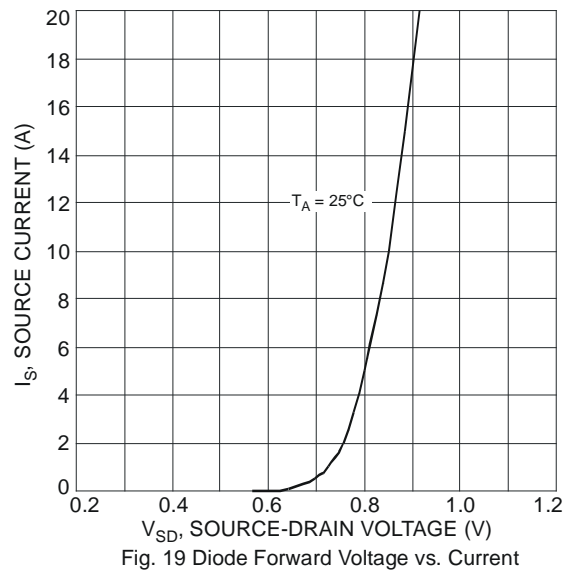
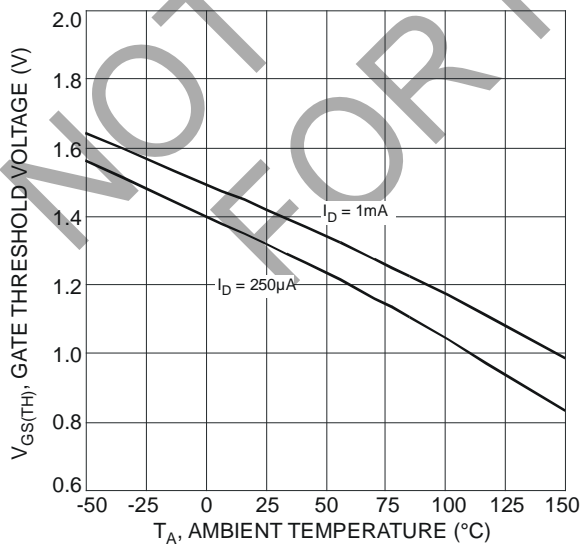
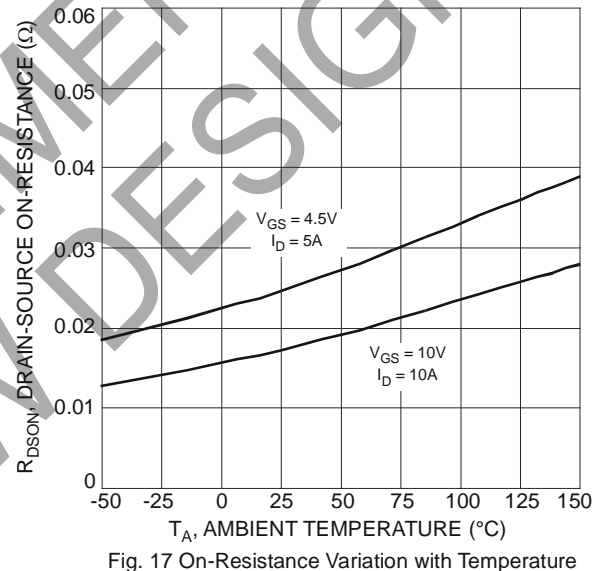
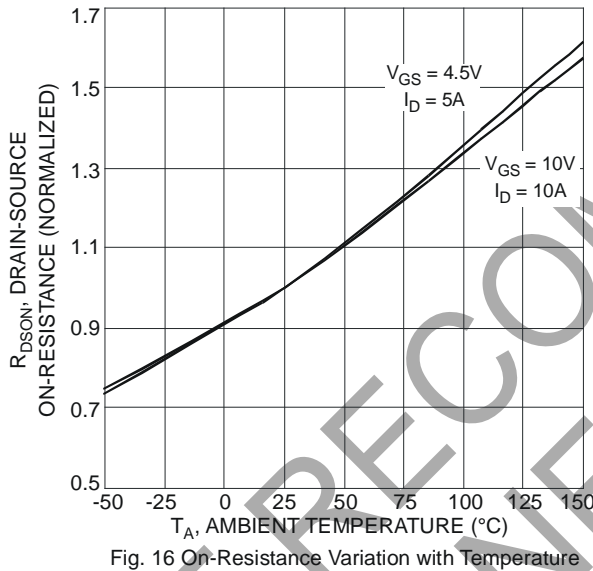
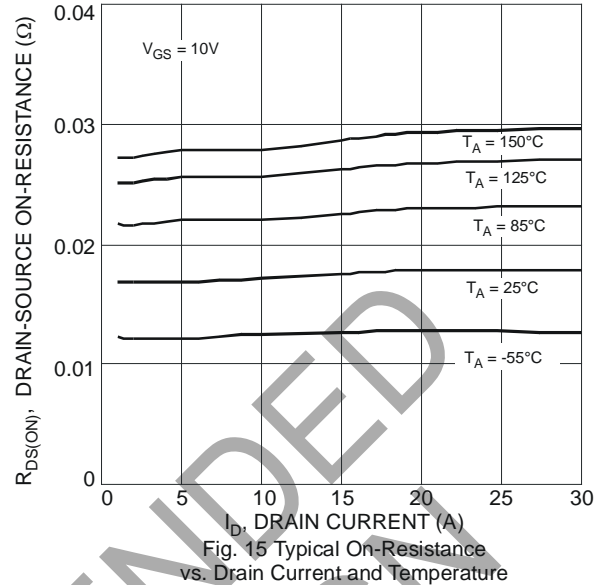
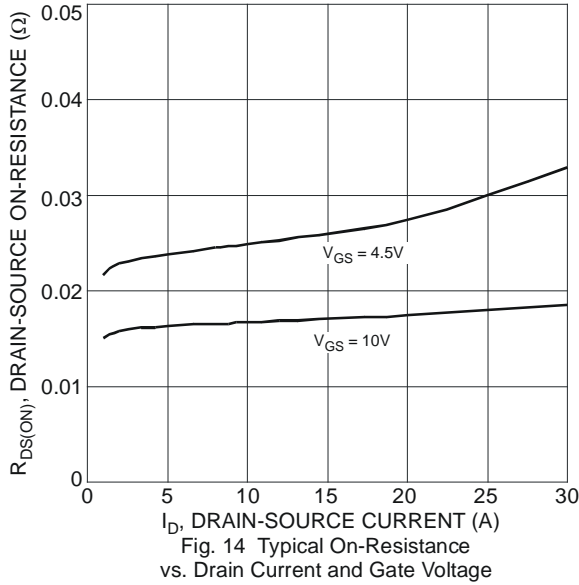
Fig. 11 Gate-Charge Characteristics

Electrical Characteristics – Q2 @ $T_A = 25^\circ\text{C}$ unless otherwise stated

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 8)						
Drain-Source Breakdown Voltage	BV_{DSS}	30	—	—	V	$V_{GS} = 0V, I_D = 250\mu A$
Zero Gate Voltage Drain Current	I_{DSS}	—	—	1.0	μA	$V_{DS} = 30V, V_{GS} = 0V$
Gate-Source Leakage	I_{GSS}	—	—	± 100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$
ON CHARACTERISTICS (Note 8)						
Gate Threshold Voltage	$V_{GS(th)}$	1.0	—	2.4	V	$V_{DS} = V_{GS}, I_D = 250\mu A$
Static Drain-Source On-Resistance	$R_{DS(on)}$	—	15	23	m Ω	$V_{GS} = 10V, I_D = 10A$
			25	33		$V_{GS} = 4.5V, I_D = 7.5A$
Forward Transfer Admittance	$ Y_{fs} $	—	2.5	—	S	$V_{DS} = 5V, I_D = 10A$
Diode Forward Voltage	V_{SD}	—	0.65	1.0	V	$V_{GS} = 0V, I_S = 1A$
DYNAMIC CHARACTERISTICS (Note 9)						
Input Capacitance	C_{iss}	—	478.9	—	pF	$V_{DS} = 15V, V_{GS} = 0V, f = 1.0MHz$
Output Capacitance	C_{oss}	—	96.7	—		
Reverse Transfer Capacitance	C_{rss}	—	61.4	—	nC	$V_{DS} = 15V, V_{GS} = 10V, I_D = 10A$
Gate Resistance	R_g	0.4	1.1	1.6		
Total Gate Charge ($V_{GS} = 4.5V$)	Q_g	—	5.0	—	ns	$V_{GS} = 10V, V_{DS} = 15V, R_G = 3\Omega, R_L = 1.5\Omega$
Total Gate Charge ($V_{GS} = 10V$)	Q_g	—	10.5	—		
Gate-Source Charge	Q_{gs}	—	1.8	—		
Gate-Drain Charge	Q_{gd}	—	1.6	—		
Turn-On Delay Time	$t_{D(on)}$	—	2.9	—	ns	
Turn-On Rise Time	t_r	—	7.9	—		
Turn-Off Delay Time	$t_{D(off)}$	—	14.6	—		
Turn-Off Fall Time	t_f	—	3.1	—		

Notes: 8. Short duration pulse test used to minimize self-heating effect.
 9. Guaranteed by design. Not subject to production testing.





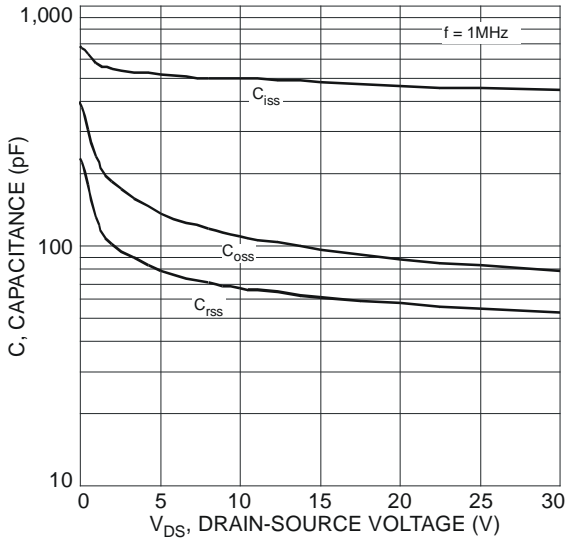


Fig. 20 Typical Total Capacitance

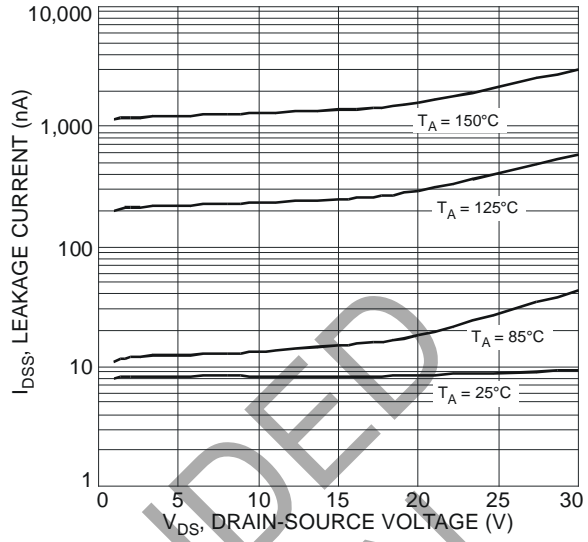


Fig. 21 Typical Leakage Current vs. Drain-Source Voltage

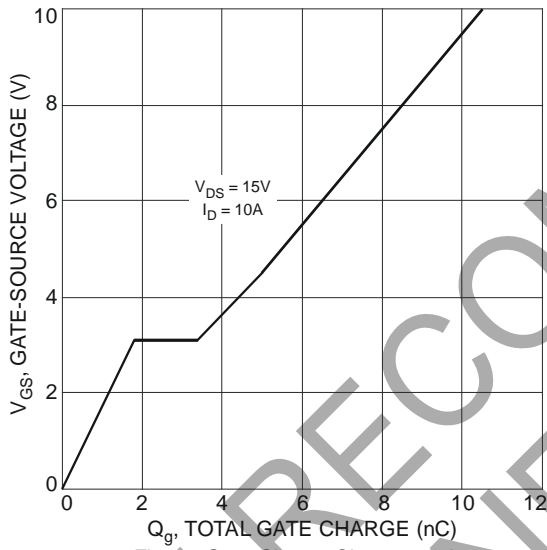


Fig. 22 Gate-Charge Characteristics

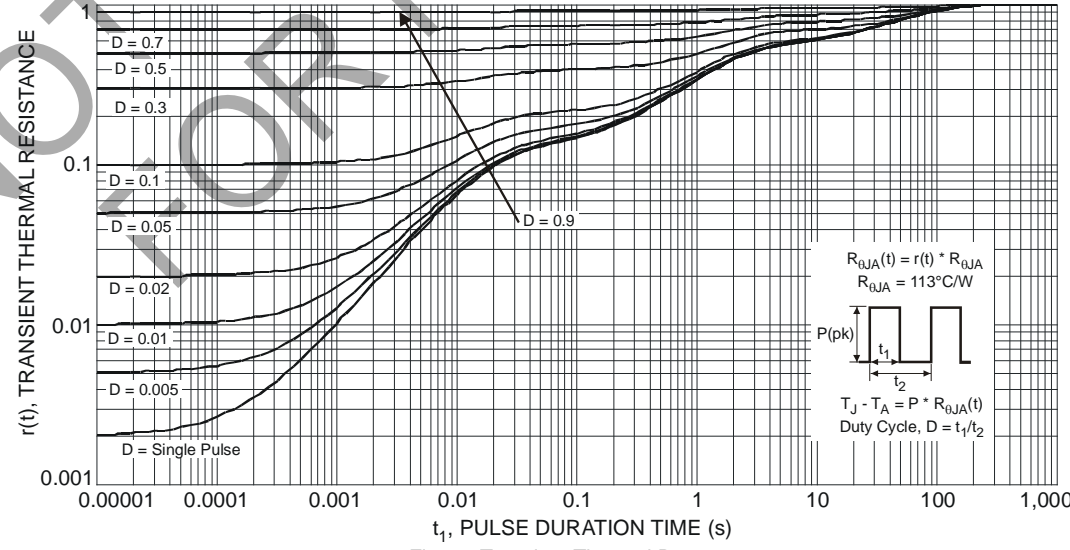


Fig. 23 Transient Thermal Response

$$R_{\theta JA}(t) = r(t) * R_{\theta JA}$$

$$R_{\theta JA} = 113^{\circ}\text{C/W}$$

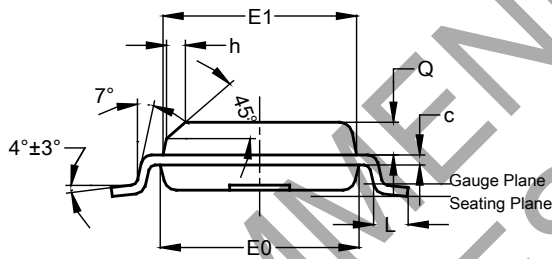
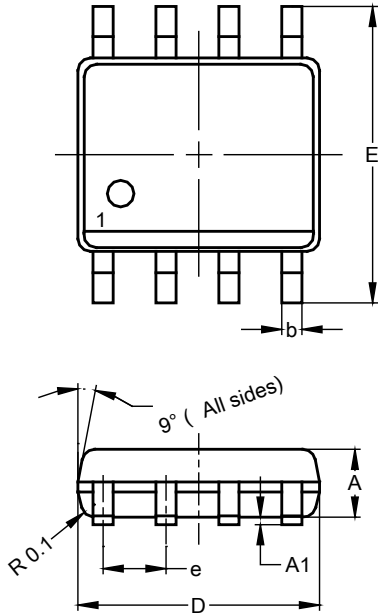
$$T_J - T_A = P * R_{\theta JA}(t)$$

$$\text{Duty Cycle, } D = t_1/t_2$$

Package Outline Dimensions

Please see <http://www.diodes.com/package-outlines.html> for the latest version.

SO-8

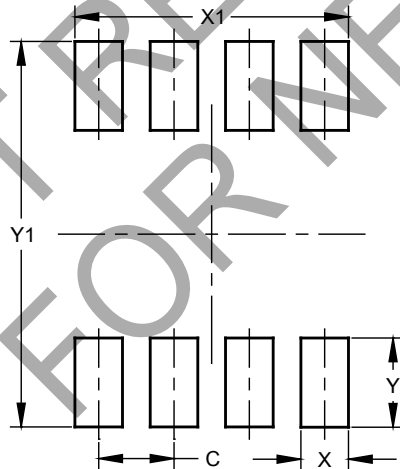


SO-8			
Dim	Min	Max	Typ
A	1.40	1.50	1.45
A1	0.10	0.20	0.15
b	0.30	0.50	0.40
c	0.15	0.25	0.20
D	4.85	4.95	4.90
E	5.90	6.10	6.00
E1	3.80	3.90	3.85
E0	3.85	3.95	3.90
e	--	--	1.27
h	--	--	0.35
L	0.62	0.82	0.72
Q	0.60	0.70	0.65
All Dimensions in mm			

Suggested Pad Layout

Please see <http://www.diodes.com/package-outlines.html> for the latest version.

SO-8



Dimensions	Value (in mm)
C	1.27
X	0.802
X1	4.612
Y	1.505
Y1	6.50

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